

### 1. Global joint venture starts operations as WeEn Semiconductors

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As from November 9th, 2015 NXP Semiconductors N.V. and Beijing JianGuang Asset Management Co. Ltd established Bipolar Power joint venture (JV), **WeEn Semiconductors**, which will be used in future Bipolar Power documents together with new contact details.

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Thank you for your cooperation and understanding,

WeEn Semiconductors





# BT151S series L and R

### **Thyristors**

Rev. 05 — 9 October 2006

**Product data sheet** 

## 1. Product profile

### 1.1 General description

Passivated thyristors in a SOT428 plastic package.

#### 1.2 Features

- High thermal cycling performance
- High bidirectional blocking voltage capability
- Surface-mounted package

### 1.3 Applications

- Motor control
- Ignition circuits

- Static switching
- Protection circuits

#### 1.4 Quick reference data

- $V_{DRM} \le 500 \text{ V (BT151S-500L/R)}$
- $V_{RRM} \le 500 \text{ V (BT151S-500L/R)}$
- $V_{DRM} \le 650 \text{ V (BT151S-650L/R)}$
- V<sub>RRM</sub> ≤ 650 V (BT151S-650L/R)
- $V_{DRM} \le 800 \text{ V (BT151S-800R)}$
- V<sub>RRM</sub> ≤ 800 V (BT151S-800R)
- $I_{TSM} \le 120 \text{ A (t = 10 ms)}$
- I<sub>T(RMS)</sub> ≤ 12 A
- $\blacksquare \quad I_{T(AV)} \le 7.5 \text{ A}$
- $I_{GT} \le 5 \text{ mA (BT151S series L)}$
- $I_{GT} \le 15 \text{ mA (BT151S series R)}$

## 2. Pinning information

Table 1. Pinning

	3		
Pin	Description	Simplified outline	Symbol
1	cathode (K)		
2	anode (A)	mb	A - K
3	gate (G)		G sym037
mb	mounting base; connected to anode	1 3	
		SOT428 (DPAK)	



# 3. Ordering information

Table 2. Ordering information

Type number	Package					
	Name	Description	Version			
BT151S-500L	DPAK	plastic single-ended surface-mounted package; 3 leads (one lead cropped)	SOT428			
BT151S-500R						
BT151S-650L						
BT151S-650R						
BT151S-800R						

# 4. Limiting values

#### Table 3. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage	BT151S-500L; BT151S-500R	<u>[1]</u> _	500	V
		BT151S-650L; BT151S-650R	<u>[1]</u> _	650	V
		BT151S-800R	-	800	V
$V_{RRM}$	repetitive peak reverse voltage	BT151S-500L; BT151S-500R	<u>[1]</u> _	500	V
		BT151S-650L; BT151S-650R	<u>[1]</u> _	650	V
		BT151S-800R	-	800	V
$I_{T(AV)}$	average on-state current	half sine wave; $T_{mb} \le 103 ^{\circ}\text{C}$ ; see Figure 1	-	7.5	А
I <sub>T(RMS)</sub>	RMS on-state current	all conduction angles; see Figure 4 and $\underline{5}$	-	12	Α
I <sub>TSM</sub>	non-repetitive peak on-state current	half sine wave; $T_j = 25$ °C prior to surge; see Figure 2 and 3			
		t = 10 ms	-	120	Α
		t = 8.3  ms	-	132	Α
I <sup>2</sup> t	I <sup>2</sup> t for fusing	t = 10 ms	-	72	A <sup>2</sup> s
dl <sub>T</sub> /dt	rate of rise of on-state current	$I_{TM} = 20 \text{ A}; I_G = 50 \text{ mA};$ $dI_G/dt = 50 \text{ mA/}\mu\text{s}$	-	50	A/μs
I <sub>GM</sub>	peak gate current		-	2	Α
$V_{RGM}$	peak reverse gate voltage		-	5	V
$P_GM$	peak gate power		-	5	W
P <sub>G(AV)</sub>	average gate power	over any 20 ms period	-	0.5	W
T <sub>stg</sub>	storage temperature		-40	+150	°C
Tj	junction temperature		-	125	°C

<sup>[1]</sup> Although not recommended, off-state voltages up to 800 V may be applied without damage, but the thyristor may switch to the on-state. The rate of rise of current should not exceed  $15A/\mu s$ .

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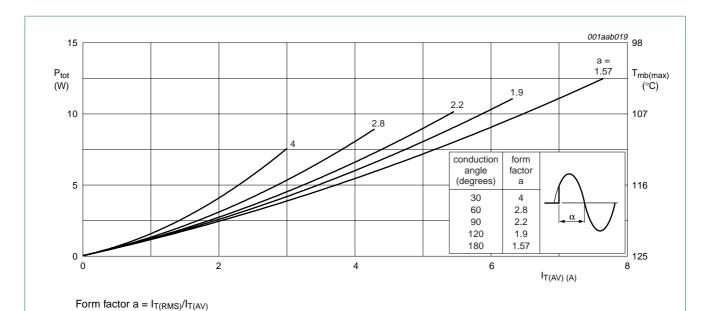


Fig 1. Total power dissipation as a function of average on-state current; maximum values

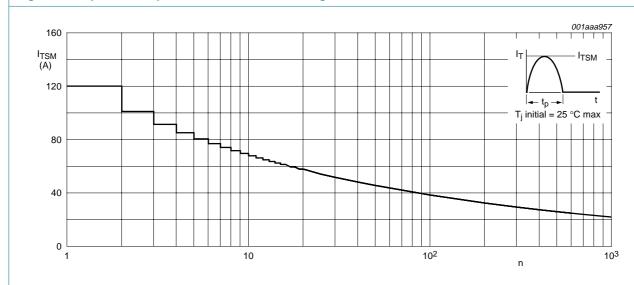


Fig 2. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

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f = 50 Hz

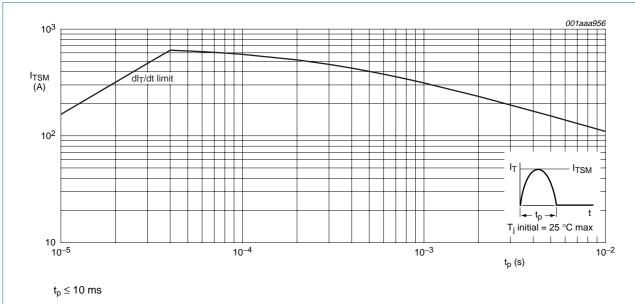


Fig 3. Non-repetitive peak on-state current as a function of pulse width for sinusoidal currents; maximum values

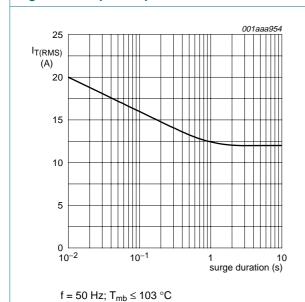


Fig 4. RMS on-state current as a function of surge duration; maximum values

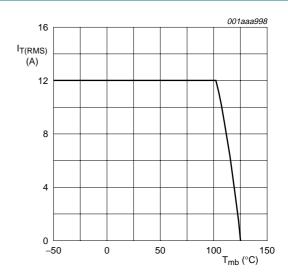


Fig 5. RMS on-state current as a function of mounting base temperature; maximum values

## 5. Thermal characteristics

Table 4. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j\text{-}mb)}$	thermal resistance from junction to mounting base	see Figure 6	-	-	1.8	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	mounted on an FR4 printed-circuit board; see Figure 14	-	75	-	K/W

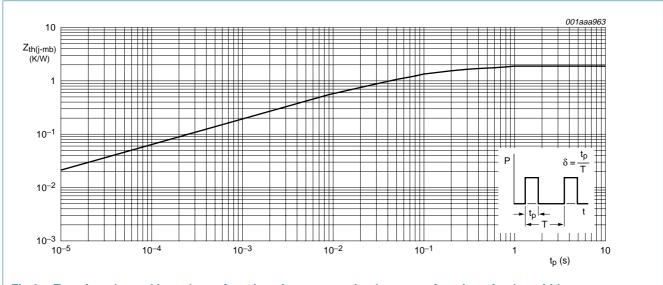


Fig 6. Transient thermal impedance from junction to mounting base as a function of pulse width

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## 6. Characteristics

**Table 5.** Characteristics  $T_i = 25 \,^{\circ}C$  unless otherwise stated.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } I_T = 100 \text{ mA; see } \frac{\text{Figure 8}}{\text{MH}}$				
		BT151S-500L	-	2	5	mA
		BT151S-500R	-	2	15	mA
		BT151S-650L	-	2	5	mΑ
		BT151S-650R	-	2	15	mΑ
		BT151S-800R	-	2	15	mΑ
IL	latching current	$V_D = 12 \text{ V; } I_{GT} = 100 \text{ mA; see}$ Figure 10	-	10	40	mA
I <sub>H</sub>	holding current	$V_D = 12 \text{ V; } I_{GT} = 100 \text{ mA; see}$ Figure 11	-	7	20	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 23 A; see <u>Figure 9</u>	-	1.4	1.75	V
$V_{GT}$	gate trigger voltage	$I_T = 100 \text{ mA}$ ; $V_D = 12 \text{ V}$ ; see Figure 7	-	0.6	1.5	V
		$I_T = 100 \text{ mA}; V_D = V_{DRM(max)};$ $T_j = 125 \text{ °C}$	0.25	0.4	-	V
I <sub>D</sub>	off-state current	$V_D = V_{DRM(max)}$ ; $T_j = 125  ^{\circ}C$	-	0.1	0.5	mΑ
I <sub>R</sub>	reverse current	$V_R = V_{RRM(max)}$ ; $T_j = 125  ^{\circ}C$	-	0.1	0.5	mΑ
Dynamic o	haracteristics					
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM} = 0.67 \times V_{DRM(max)}$ ; $T_j = 125$ °C; exponential waveform; see Figure 12				
		$R_{GK} = 100 \Omega$	200	1000	-	V/μs
		gate open circuit	50	130	-	V/μs
t <sub>gt</sub>	gate-controlled turn-on time	$I_{TM} = 40 \text{ A}; V_D = V_{DRM(max)};$ $I_G = 100 \text{ mA}; dI_G/dt = 5 \text{ A/}\mu\text{s}$	-	2	-	μs
t <sub>q</sub>	commutated turn-off time	$V_{DM} = 0.67 \times V_{DRM(max)}; T_j = 125 ^{\circ}C;$ $I_{TM} = 20  A; V_R = 25  V;$ $(dI_T/dt)_M = 30  A/\mu s; dV_D/dt = 50  V/\mu s;$ $R_{GK} = 100  \Omega$	-	70	-	μs

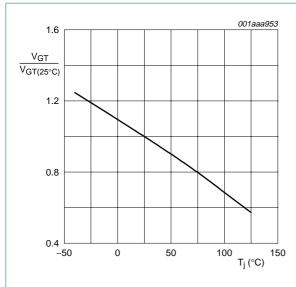


Fig 7. Normalized gate trigger voltage as a function of junction temperature

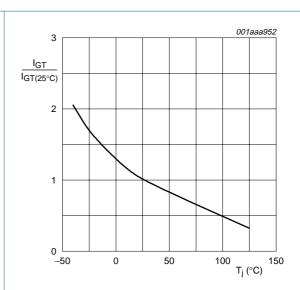
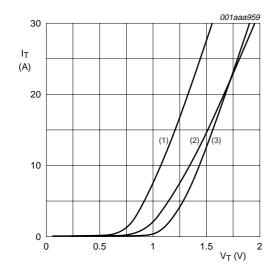


Fig 8. Normalized gate trigger current as a function of junction temperature



 $V_0 = 1.06 \text{ V}$ 

 $R_s = 0.0304 \Omega$ 

- (1)  $T_i = 125 \,^{\circ}\text{C}$ ; typical values
- (2) T<sub>i</sub> = 125 °C; maximum values
- (3)  $T_i = 25$  °C; maximum values

Fig 9. On-state current as a function of on-state voltage

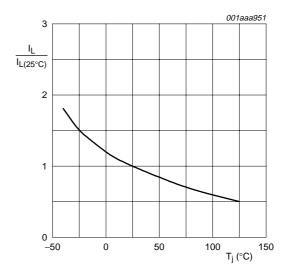


Fig 10. Normalized latching current as a function of junction temperature

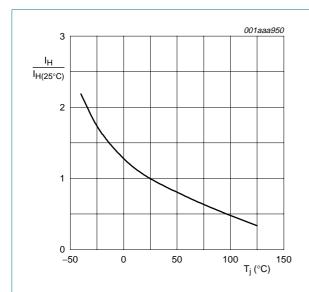
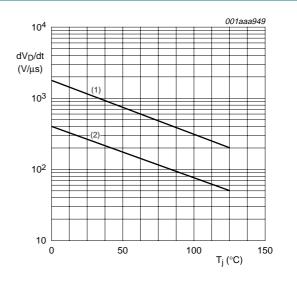


Fig 11. Normalized holding current as a function of junction temperature



- (1)  $R_{GK} = 100 \Omega$
- (2) Gate open circuit

Fig 12. Critical rate of rise of off-state voltage as a function of junction temperature; minimum values

## 7. Package outline

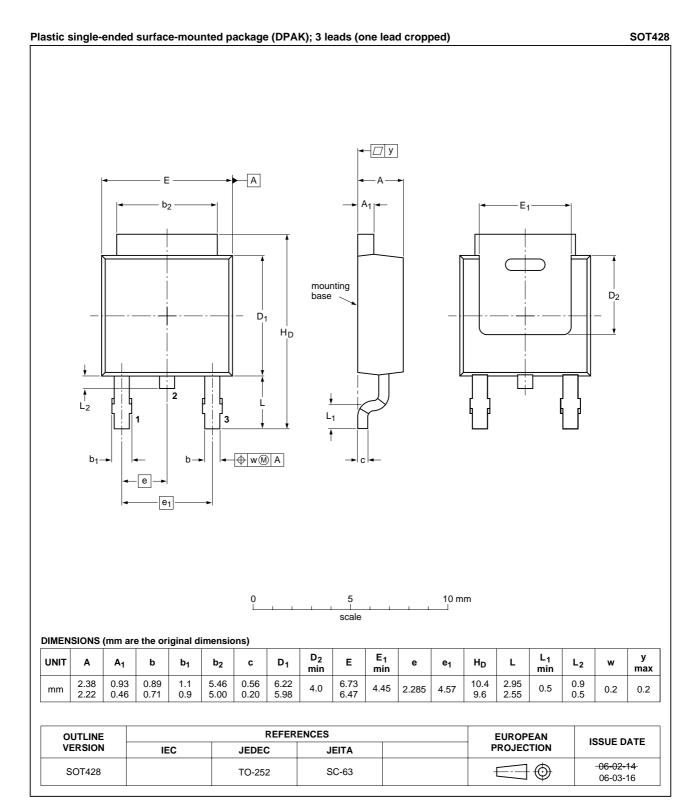
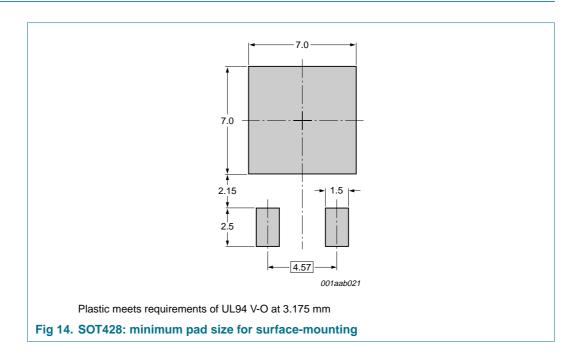


Fig 13. Package outline SOT428 (DPAK)

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# 8. Mounting



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# 9. Revision history

### Table 6. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BT151S_SER_L_R_5	20061009	Product data sheet	-	BT151S_SERIES_4
Modifications:		of this data sheet has been of NXP Semiconductors.	redesigned to comply v	with the new identity
	<ul> <li>Legal texts</li> </ul>	have been adapted to the n	ew company name whe	ere appropriate.
	<ul> <li>Added type</li> </ul>	numbers BT151S-500L and	d BT151S-650L	
BT151S_SERIES_4 (9397 750 13161)	20040609	Product specification	-	BT151S_SERIES_3
BT151S_SERIES_3	20020101	Product specification	-	BT151S_SERIES_2
BT151S_SERIES_2	19990601	Product specification	-	BT151S_SERIES_1
BT151S_SERIES_1	19970901	Product specification	-	-

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#### 10.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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